

**Search Notes**

Application/Control No.

10/705,347

Examiner

Kin-Chan Chen

Applicant(s)/Patent under  
Reexamination

LABELLE ET AL.

Art Unit

1765

**SEARCHED**

| Class | Subclass | Date     | Examiner |
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| 438   | 694      | 8/2/2005 | KCC      |
|       | 696      |          |          |
|       | 706      |          |          |
|       | 710      |          |          |
|       | 714      |          |          |
|       | 719      |          |          |
|       | 720      |          |          |
| 438   | 722      | 8/2/05   | K-cc     |
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**INTERFERENCE SEARCHED**

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

|  | DATE     | EXMR |
|--|----------|------|
| EAST key words search, USPAT, US-PGPUB, EPO, JPO, Derwent, IBM-TDB, inventor search. | 8/1/2005 | KCC  |
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